Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/676,961	PON ET AL.	
Examiner	Art Unit	
Chris C. Chu	2815	

SEARCHED			
Class	Subclass	Date	Examiner
257	E25.031, E25.032 & E23.042	12/22/2005	C.C.
257	777 & 686	12/22/2005	C.C.
438	FOR368	12/22/2005	C.C.
438	FOR426	12/22/2005	C.C.
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB;	12/22/2005	C.C.
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